

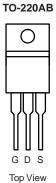
ROHS COMPLIANT

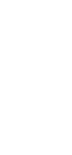
HM3307B-VB Datasheet N-Channel 60 V (D-S) MOSFET

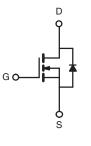
PRODUCT SUMMARY					
V _{DS} (V)	60				
$R_{DS(on)}(\Omega)$ at $V_{GS} = 10 V$	0.003				
$R_{DS(on)} (\Omega)$ at $V_{GS} = 4.5 V$	0.009				
I _D (A)	210				
Configuration	Single				

FEATURES

- Halogen-free According to IEC 61249-2-21
 Definition
- Trench Power MOSFET
- Package with Low Thermal Resistance
- 100 % R_g and UIS Tested
- Compliant to RoHS Directive 2002/95/EC







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T	_C = 25 °C, unles	s otherwise noted)		
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V _{DS}	60	V	
Gate-Source Voltage		V _{GS}	± 20	V	
Continuous Drain Current	T _C = 25 °C		210		
	T _C = 125 °C	I _D	120 ^a		
Continuous Source Current (Diode Conduction) ^a		I _S	120 ^a	А	
Pulsed Drain Current ^b		I _{DM}	480		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	75		
Single Pulse Avalanche Energy	L = 0.1 MH	E _{AS}	281	mJ	
	T _C = 25 °C	PD	375	W	
Maximum Power Dissipation ^b	T _C = 125 °C		125	٧V	
Operating Junction and Storage Temperature Rat	nge	T _J , T _{stg}	- 55 to + 175	°C	

THERMAL RESISTANCE RATINGS				
PARAMETER		SYMBOL	LIMIT	UNIT
Junction-to-Ambient	PCB Mount ^c	R _{thJA}	40	°C/W
Junction-to-Case (Drain)		R _{thJC}	0.4	0/10

Notes

a. Package limited.

b. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$

c. When mounted on 1" square PCB (FR-4 material).

d. Parametric verification ongoing.

Static Number of the state of	SPECIFICATIONS ($T_C = 25 \ ^{\circ}C$, unless otherv	vise noted)						
$ \begin{array}{ c c c c c } \hline \begin{tabular}{ c c c } \hline \begin{tabular}{ c c c c } \hline \hline \begin{tabular}{ c c c c c c c } \hline \hline \begin{tabular}{ c c c c c c c } \hline \hline \begin{tabular}{ c c c c c c } \hline \hline \begin{tabular}{ c c c c c c c c c c c c c c c c c c c$	PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
$ \begin{array}{c c c c c c c } \hline Gate-Source Threshold Voltage $V_{GS(th)}$ & $V_{DS} = V_{SS}, I_D = 250 \ \mu A$ & 2.0 & $-$ & 3.5 \\ \hline Gate-Source Leakage I_{GSS} & $V_{DS} = 0 \ V, V_{GS} = \pm 20 \ V$ & $-$ & $-$ & ± 100 \\ \hline V_{GS} = 0 \ V$ & $V_{DS} = 60 \ V$ & $-$ & $-$ & $-$ & 50 \\ \hline V_{GS} = 0 \ V$ & $V_{DS} = 60 \ V, $T_J = 125 \ C$ & $-$ & $	Static	•					•		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0, I _D = 250 μA	60	-	-	v	
$ \begin{array}{ c c c c c } \hline Zero Gate Voltage Drain Current \\ I_{DSS} & V_{GS} = 0 & V_{DS} = 60 & V, T_J = 125 \ ^{\circ}{\rm C} & - & - & 350 \\ \hline V_{GS} = 0 & V_{DS} = 60 & V, T_J = 125 \ ^{\circ}{\rm C} & - & - & 350 \\ \hline V_{GS} = 0 & V_{DS} = 60 & V, T_J = 175 \ ^{\circ}{\rm C} & - & - & 350 \\ \hline V_{GS} = 0 & V_{DS} = 60 & V, T_J = 175 \ ^{\circ}{\rm C} & - & - & 350 \\ \hline V_{GS} = 10 & V_{DS} = 50 & 120 & - & - & 0.003 & - & 0.003 & - & 0.003 & - & 0.008 & - & 0.009 & - & 0.008 & - & 0.008 & - & 0.009 & - & 0.008 & - & 0.009 & - & 0.008 & - & 0.009 & - & 0.008 & - & 0.009 & - & 0.008 & - & 0.009 & - & 0.008 & - & 0.009 & - & 0.008 & - & 0.009 & - & 0.008 & - & 0.009 & - & 0.008 & - & 0.009 & - & 0.008 & - & 0.009 & - & 0.008 & - & 0.009 & - & 0.008 & - & 0.009 & - & 0.008 & - & 0.009 & - & 0.008 & - & 0.009 & - & 0.008 & - & 0.009 & - & 0.000 & - & 0.000 & - & 0.000 & - & 0.000 & - & 0.000 & - & 0.000 & - & 0.000 & - & 0.000 & - & 0.000 & - & 0.000 & - & 0.000 & - & 0.000 & - & 0.000 & - & 0.00$	Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μΑ	2.0	-	3.5		
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	Gate-Source Leakage	I _{GSS}	V _{DS} =	$= 0 \text{ V}, \text{ V}_{\text{GS}} = \pm 20 \text{ V}$	-	-	± 100	nA	
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$			$V_{GS} = 0 V$	V _{DS} = 60 V	-	-	1.0		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V$	V _{DS} = 60 V, T _J = 125 °C	-	-	50	μA	
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$			$V_{GS} = 0 V$	V _{DS} = 60 V, T _J = 175 °C	-	-	350		
$ \begin{array}{ c c c c c c } \hline Pain-Source On-State Resistance^{a} \\ \hline Pain-Source On-State Resistance^{b} \\ \hline Pain-Source On-State Resistance \\ \hline Pain-Source Pain-State Resistance \\ \hline Pain-Source Pain-State Resistance \\ \hline Pain$	On-State Drain Current ^a	I _{D(on)}	$V_{GS} = 10 V$	$V_{DS} \ge 5 V$	120	-	-	А	
$ \begin{array}{ c c c c c } \hline Pain-Source On-State Resistance^a \\ \hline Pain-Source On-State Resistance^b \\ \hline Pain-Source On-State Resistance^b \\ \hline Pain-Source On-State Resistance^b \\ \hline Pain-Source On-State Resistance \\ \hline Pain-Source Charge^c \\ \hline Case - Crase \\ \hline Pain-Source Charge^c \\ \hline Case - Crase $			$V_{GS} = 10 V$	I _D = 30 A	-	0.003	-	Ω	
$ \begin{array}{ c c c c c c c } \hline V_{GS} = 10 \ V & _{D} = 30 \ A, \ T_{J} = 175 \ ^{\circ}C & - & 0.008 & - \\ \hline V_{GS} = 4.5 \ V & _{D} = 20 \ A & - & 0.009 & - \\ \hline V_{GS} = 4.5 \ V & _{D} = 20 \ A & - & 109 & - \\ \hline Dynamic^b & & & & & & & & & & & & & & & & & & &$	Durain Source On State Desistance?		V _{GS} = 10 V	I _D = 30 A, T _J = 125 °C	-	0.006	-		
$ \begin{array}{ c c c c c } \hline Forward Transconductance^b & g_{fs} & V_{DS} = 15 \ V, \ I_{D} = 30 \ A & - & 109 & - \\ \hline \ $	Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 10 V$	I _D = 30 A, T _J = 175 °C	-	0.008	-		
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$			$V_{GS} = 4.5 V$	I _D = 20 A	-	0.009	-		
$ \begin{array}{ c c c c } \hline Input Capacitance & C_{iss} \\ \hline Output Capacitance & C_{oss} \\ \hline Output Capacitance & C_{oss} \\ \hline Reverse Transfer Capacitance & C_{rss} \\ \hline Input Capacitance & C_{rss} \\ \hline V_{GS} = 0 \ V \\ \hline V_{DS} = 25 \ V, \ f = 1 \ MHz \\ \hline V_{DS} = 25 \ V, \ f = 1 \ MHz \\ \hline Input Capacitance & C_{rss} \\ \hline Input Capacitance & C	Forward Transconductanceb	g _{fs}	V _{DS} = 15 V, I _D = 30 A		-	109	-	S	
$ \begin{array}{ c c c c c c } \hline Output Capacitance & C_{oss} & V_{GS} = 0 \ V & V_{DS} = 25 \ V, \ f = 1 \ MHz & - & 1000 & - & - & 750 & - & - & - & 750 & - & - & - & 750 & - & - & - & 750 & - & - & - & - & - & - & - & - & - & $	Dynamic ^b	•							
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	Input Capacitance	C _{iss}			-	9300	-		
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Output Capacitance	C _{oss}	$V_{GS} = 0 V$	V _{DS} = 25 V, f = 1 MHz	-	1000	-	pF	
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	Reverse Transfer Capacitance	C _{rss}			-	750	-		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Total Gate Charge ^c	Qg			-	180	-		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Charge ^c	Q _{gs}	V _{GS} = 10 V	$V_{DS} = 30 \text{ V}, \text{ I}_{D} = 110 \text{ A}$	-	24.7	-	nC	
$ \begin{array}{ c c c c c c } \hline Turn-On \ Delay \ Time^{\circ} & t_{d(on)} & & & & & & & & & & & & & & & & & & &$	Gate-Drain Charge ^c	Q _{gd}			-	50.4	-		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate Resistance	R _g	f = 1 MHz		0.5	1.1	1.6	Ω	
$\begin{tabular}{ c c c c c c c c c c c c c c c c c c c$	Turn-On Delay Time ^c	t _{d(on)}			-	19	29		
$\begin{tabular}{ c c c c c c c c c c c c c c c c c c c$	Rise Time ^c				-	23	35	- ns	
Fall Time ^c t _f - 35 53 Source-Drain Diode Ratings and Characteristics ^b Pulsed Current ^a I _{SM} - - 480	Turn-Off Delay Time ^c	t _{d(off)}			-	83	125		
Pulsed Current ^a I _{SM} 480	Fall Time ^c				-	35	53		
	Source-Drain Diode Ratings and Char	acteristics ^b							
Forward Voltage V _{SD} I _E = 100 A, V _{GS} = 0 - 0.9 1.5	Pulsed Current ^a	I _{SM}			-	-	480	Α	
	Forward Voltage	V _{SD}	I _F =	= 100 A, V _{GS} = 0	-	0.9	1.5	V	

Notes

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

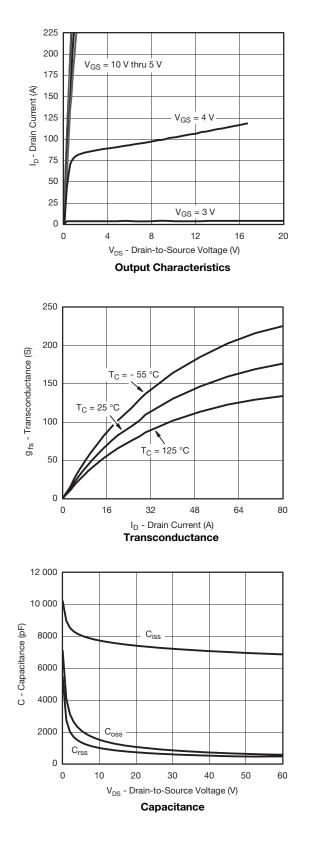
c. Independent of operating temperature.

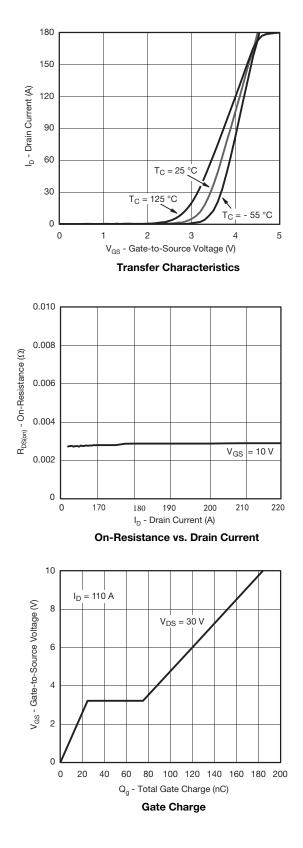
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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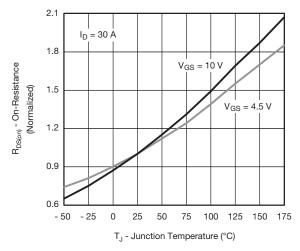
TYPICAL CHARACTERISTICS ($T_A = 25$ °C, unless otherwise noted)



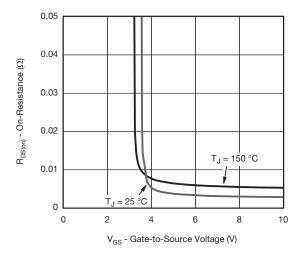




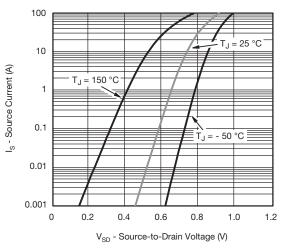
TYPICAL CHARACTERISTICS ($T_A = 25 \text{ °C}$, unless otherwise noted)



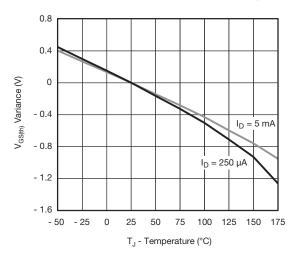




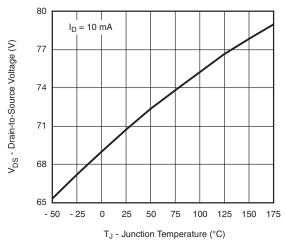
On-Resistance vs. Gate-to-Source Voltage



Source Drain Diode Forward Voltage



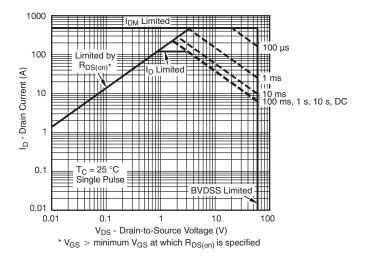




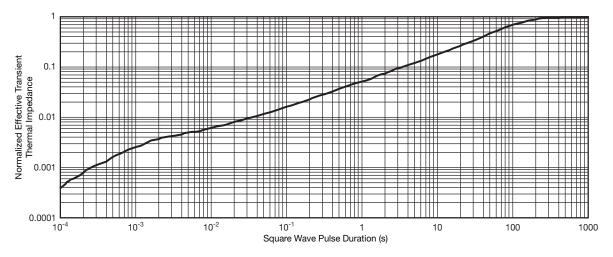
Drain Source Breakdown vs. Junction Temperature



THERMAL RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted)



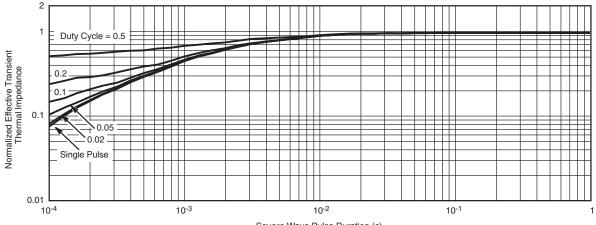
Safe Operating Area



Normalized Thermal Transient Impedance, Junction-to-Ambient



THERMAL RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted)



Square Wave Pulse Duration (s)

Normalized Thermal Transient Impedance, Junction-to-Case

Note

• The characteristics shown in the two graphs

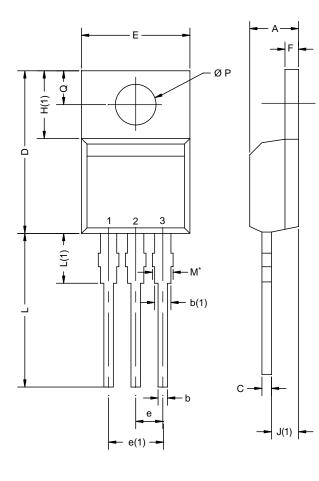
- Normalized Transient Thermal Impedance Junction-to-Ambient (25 °C)

- Normalized Transient Thermal Impedance Junction-to-Case (25 °C)

are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board - FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions.



TO-220AB



	MILLIM	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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